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Australian Standard®

Fixed resistors for use in electronic equipment

Part 1: Terms and methods of test—Generic specification

[IEC title: Fixed resistors for use in electronic equipment
Part 1: Generic specification]



STANDARDS AUSTRALIA 

This Australian Standard was prepared by Committee TE/2, Passive Electronic Equipment. It was approved on behalf of the Council of Standards Australia on 19 September 1989 and published on 15 April 1991.

The following interests are represented on Committee TE/2:

Australian Electrical and Electronics Manufacturers Association
Confederation of Australian Industry
Department of Defence
Department of Industry, Technology and Commerce
Institution of Radio and Electronics Engineers Australia
National Association of Testing Authorities Australia
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Australian Standard®

Fixed resistors for use in electronic equipment

Part 1: Terms and methods of test—Generic specification

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PREFACE

This Standard was prepared by the Standards Australia Committee on Passive Electronics Components to supersede AS 1352.1—1977. It is reproduced from IEC 115-1:1982 as amended by Amendments 1 (1983), 2 (1987), and 3 (1989), as one of a series of Standards to be published on passive electronic components.

The purpose of the new edition is to define standard terms and specify inspection procedures and methods of tests for use in specifications for qualification approval in quality assessment systems such as the IECQ. The amendments add to the tests in regard to overload tests for low power resistors and high voltage pulse tests.

This Standard includes test and measurement procedures in standard atmospheric conditions, a climatic sequence and endurance tests as well as the standard tests appropriate to resistance testing and solderability.

For the purpose of this Australian Standard, the text of the IEC Standard used herein should be modified as follows:

- (a) **Terminology:** The words 'Australian Standard' should replace the words 'IEC Publication' wherever they appear.
- (b) **References:** The references to International Standards should be replaced by references to Australian Standards as follows:

<i>Reference to International Standard</i>		<i>Appropriate Australian Standard</i>	
IEC 27	Letter symbols to be used in electrical technology	AS 1046	Letter symbols to be used in electrical technology
IEC 27-1	Part 1: General	AS 1046.1	Part 1: General
IEC 50	International electrotechnical vocabulary (IEV)	AS 1852	International electrotechnical vocabulary (IEV)
IEC 62	Marking codes for resistors and capacitors	AS 2066	Marking codes for resistors and capacitors
IEC 63	Preferred number series for resistors and capacitors	AS 2065	Preferred number series for resistors and capacitors
IEC 60	High voltage test techniques	AS 1931	High voltage test techniques
IEC 60-1	Part 1: General definitions and test requirements	AS 1931.1	Part 1: General definitions, test requirements, test procedures and measuring devices
IEC 60-2	Part 2: Test procedures		
IEC 68	Basic environmental testing procedures	AS 1099	Basic environmental testing procedures for electrotechnology
IEC 68-1	Part 1: General	AS 1099.1	General
IEC 68-2	Part 2: Tests	AS 1099.2	Tests
IEC 117	Recommended graphical symbols	AS 1102	Graphical symbols for electrotechnology
IEC 195	Method of measurement of current noise generated in fixed resistors	—	
IEC 410	Sampling plans and procedures for inspection by attributes	AS 1199	Sampling plans and procedures for inspection by attributes
QC 001001	Basic rules for the IEC quality assessment system for electronic components (IECQ)	—	
QC 001002	Rules of procedure of the IEC quality assessment system for electronic components (IECQ)	—	
ISO Standard 3	Preferred numbers—Series of preferred numbers	AS 2752	Preferred numbers and their use
ISO Standard 497	Guide to the choice of series of preferred numbers and of series containing more rounded values of preferred numbers	AS 2752	Preferred numbers and their use
ISO Standard 1000	SI units and recommendations for the use of their multiples and of certain other units	AS 1000	The international system of units (SI) and its application

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STANDARDS AUSTRALIA

Australian Standard

Fixed resistors for use in electronic equipment

Part 1: Terms and methods of test—Generic specification

1. Scope

This standard is applicable to fixed resistors for use in electronic equipment.

It establishes standard terms, inspection procedures and methods of test for use in sectional and detail specifications for qualification approval and for quality assessment systems for electronic components.

SECTION TWO — GENERAL

2. General

2.1 *Related documents**IEC Publications*

Publication 27-1: (1971)	Letter Symbols to be Used in Electrical Technology. Part 1: General.
Publication 50:	International Electrotechnical Vocabulary (I.E.V.).
Publication 62: (1974)	Marking Codes for Resistors and Capacitors.
Publication 63: (1963)	Preferred Number Series for Resistors and Capacitors.
	Amendment No. 1: (1967)
	Amendment No. 2: (1977)
Publication 68:	Basic Environmental Testing Procedures.
Publication 68-1: (1978)	Part 1: General.
Publication 68-2-1: (1974)	Tests A: Cold.
Publication 68-2-1A: (1976)	First supplement.
Publication 68-2-2: (1974)	Tests B: Dry Heat.
Publication 68-2-2A: (1976)	First supplement.
Publication 68-2-3: (1969)	Test Ca: Damp Heat, Steady State.
Publication 60-1 (1973)	High-voltage test techniques. Part 1: General definitions and test requirements.
Publication 60-2 (1973)	Part 2: Test procedures.